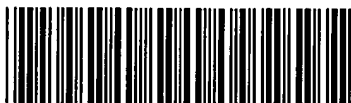


Search Notes

Application/Control No.

10/606,270

Examiner

Tianjie Chen

Applicant(s)/Patent under
Reexamination

SHIBATA, MICHIIRO

Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner
Updated		8/30/2006	TJ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR